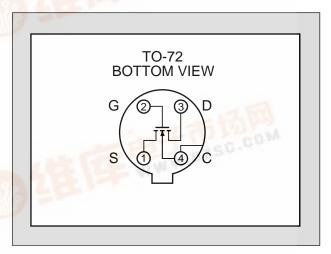


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FEATURES					
DIRECT REPLACEMENT FOR INTERSIL 2N4351					
HIGH DRAIN CURRENT	$I_D = 100 \text{mA}$				
HIGH GAIN	g _{fs} = 1000µS				
ABSOLUTE MAXIMUM RATINGS ¹					
@ 25 °C (unless otherwise stated)					
Maximum Temperatures					
Storage Temperature	-65 to +200 °C				
Operating Junction Temperature	-55 to +150 °C				
Maximum Power Dissipation					
Continuous Power Dissipation	375mW				
Maximum Current					
Drain to Source	100mA				
Maximum Voltages					
Drain to Body	25V				
Drain to Source	25V				
Peak Gate to Source ²	±125V				

2N4351

N-CHANNEL MOSFET ENHANCEMENT MODE



^{*} Body tied to Case.

ELECTRICAL CHARACTERISTICS @ 25 °C (unless otherwise stated) (V_{SB} = 0V unless otherwise stated)

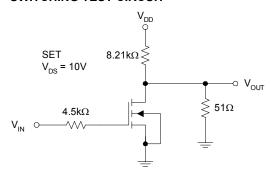
SYMBOL	CHARACTERISTIC	MIN	TYP	MAX	UNITS	CONDITIONS
BV _{DSS}	Drain to Source Breakdown Voltage	25				$I_D = 10 \mu A, V_{GS} = 0 V$
V _{DS(on)}	Drain to Source "On" Voltage			1	V	I _D = 2mA, V _{GS} = 10V
$V_{GS(th)}$	Gate to Source Threshold Voltage	1		5		$V_{DS} = 10V, I_{D} = 10\mu A$
I _{GSS}	Gate Leakage Current			10	рА	$V_{GS} = \pm 30V, V_{DS} = 0V$
I _{DSS}	Drain Leakage Current "Off"			10	nA	V _{DS} = 10V, V _{GS} = 0V
I _{D(on)}	Drain Current "On"	3			mA	V _{GS} = 10V, V _{DS} = 10V
g fs	Forward Transconductance	1000			μS	$V_{DS} = 10V, I_{D} = 2mA, f = 1MHz$
r _{DS(on)}	Drain to Source "On" Resistance			300	Ω	$V_{GS} = 10V, I_D = 0A, f = 1kHz$
C _{rss}	Reverse Transfer Capacitance		110	1.3		$V_{DS} = 0V, V_{GS} = 0V, f = 140kHz$
C _{iss}	Input Capacitance			5.0	pF	V _{DS} = 10V, V _{GS} = 0V, <i>f</i> = 140kHz
$C_{\sf db}$	Drain to Body Capacitance			5.0		V _{DB} = 10V, <i>f</i> = 140kHz
	A LE WWW.DZSD.CO					



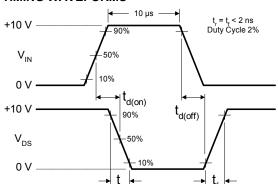
SWITCHING CHARACTERISTICS

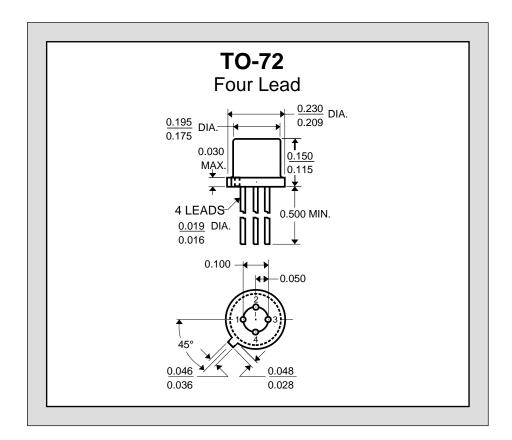
SYMBOL	CHARACTERISTIC	MAX	UNITS		
$t_{d(on)}$	Turn On Delay Time	45			
t _r	Turn On Rise Time	65	20		
$t_{d(off)}$	Turn Off Delay Time	60	ns		
t _f	Turn Off Fall Time	100			

SWITCHING TEST CIRCUIT



TIMING WAVEFORMS





- 1. Absolute maximum ratings are limiting values above which serviceability may be impaired.
- 2. Device must not be tested at $\pm 125 \text{V}$ more than once or longer than 300ms.

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